| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|----------|------|--|----------|---------------------|---------|------------------|
| L25 | 1 | ((((first and second) (a plurality of)) with (((equally near2 sized) equivalent) near4 (group circuit)) with (interface near3 (circuit device unit))) and ((creat\$3 generat\$3) near4 (test\$3 adj signal)) and (receiv\$3 near3 (test\$3 adj signal)).clm. | US-PGPUB | OR | ON | 2007/06/19 15:11 |

Interference Search History Printout

| Ref # | Hịts | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|----------|------|--|---|---------------------|---------|------------------|
| L25 | 1 | ((((first and second) (a plurality of)) with (((equally near2 sized) equivalent) near4 (group circuit)) with (interface near3 (circuit device unit))) and ((creat\$3 generat\$3) near4 (test\$3 adj signal)) and (receiv\$3 near3 (test\$3 adj signal)).clm. | US-PGPUB | OR | ON | 2007/06/19 15:11 |
| L22 | 241 | micron.as. and (interface near3 (circuit buffer device IO)).ab. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 15:02 |
| L24 | 1 | micron.as. and (interface near3 (circuit buffer device IO)).ab. and loop adj back | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 14:48 |
| L23 | 0 | micron.as. and (interface near3 (circuit buffer device IO)).ab. and LFSR and MISR | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 14:41 |
| L21 | 28 | ("20010016929" "20030035473" "2 0030043752" "20030149921" "3916 379" "5956370" "6028845" "620182 9" "6385236" "6385738" "6693881" "5787114" "6834367").PN. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 14:39 |
| L20 | 15 | ("20050076280" "5726991" "62018 29" "6834367" "6977960" "7093172 " "7111208").PN. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 14:03 |
| L18 | 1 | ((714/25,30,43,44,724,728, 733-735,738,739,742).ccls.) and (LFSR ((data signal) near2 generat\$3)) and (MISR compactor ((genrat\$3 calculat\$3) near3 signature)) and (group with (interface adj (circuit device group cell))) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 14:00 |
| L19 | 6 | L17 not L16 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 12:56 |

| L17 | 14 | ((714/25,30,43,44,724,728, 733-735,738,739,742).ccls.) and (LFSR ((data signal) near2 generat\$3)) and (MISR compactor ((genrat\$3 calculat\$3) near3 signature)) and (interface adj (circuit device group cell)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 12:56 |
|-----|-------|--|---|------|------------------|------------------|
| L16 | 8 | ((714/25,30,43,44,724,728, 733-735,738,739,742).ccls.) and ((LFSR ((data signal) near2 generat\$3)) same (MISR compactor)) and (interface adj (circuit device group cell)) | | ON | 2007/06/19 12:54 | |
| L15 | . 356 | ((714/25,30,43,44,724,728, 733-735,738,739,742).ccls.) and (LFSR ((data signal) near2 generat\$3)) and (MISR compactor compar\$3) and (interface adj (circuit device group cell)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR . | ON | 2007/06/19 12:52 |
| L14 | 5 | ((714/25,30,43,44,724,728, 733-735,738,739,742).ccls.) and LFSR and MISR and (interface adj (circuit device group cell)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 12:47 |
| L12 | 10185 | ((714/25,30,43,44,724,728, 733-735,738,739,742).ccls.) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 12:32 |
| L13 | 5 | L12 and L11 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 12:31 |
| L11 | 10 | ((((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 12:31 |

| S10 6 | 5 | ((714/25,30,43,44,724,728, 733-735,738,739,742).ccls.) and (((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/19 12:30 |
|----------|---|--|---|----|----|------------------|
| S10 5 | 5 | ((714/25,30,43,44,724,728, 733-735,738,739,742).ccls.) and (((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not ((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/05 10:45 |
| S88 | | ((714/25,30,43,44,724,728, 733-735,738,739,742).ccls.) and (((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not ((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/26 12:01 |

| S10 4 | | ((714/25,30,43,44,724,728, 733-735,738,739,742).ccls.) and (((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/03/04 16:19 |
|----------|---|--|---|------|----|------------------|
| S10 3 | 1 | "4503537".PN. | USPAT; USOCR | OR | ON | 2005/03/04 13:20 |
| S10 2 | 1 | "5230000".PN. | USPAT; USOCR | OR | ON | 2005/03/04 13:19 |
| S10 1 | 1 | "5260946".PN. | USPAT; USOCR | OR | ON | 2005/03/04 13:18 |
| S10 0 | 1 | "5659312".PN. | USPAT; USOCR | OR | ON | 2005/03/04 13:18 |
| S99 | 1 | "5706296".PN. | USPAT; USOCR | OR | ON | 2005/03/04 13:16 |
| S98 | 1 | "6119250".PN. | USPAT; USOCR | OR . | ON | 2005/03/04 13:15 |
| S97 | 1 | "6313656".PN. | USPAT; USOCR | OR | ON | 2005/03/04 13:15 |
| S96 | 2 | "6675322".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/03/04 13:15 |
| S95 | 1 | "5381421".PN. | USPAT; USOCR | OR | ON | 2005/03/04 10:10 |
| S94 | 1 | "5400057".PN. | USPAT; USOCR | OR | ON | 2005/03/04 10:09 |
| S93 | 1 | "5225774".PN. | USPAT; USOCR | OR . | ON | 2005/03/04 10:08 |
| S92 | 1 | "5230001".PN. | USPAT; USOCR | OR | ON | 2005/03/04 10:07 |
| S91 | 1 | "5459733".PN. | USPAT; USOCR | OR | ON | 2005/03/04 10:06 |
| S90 | 1 | "5621739".PN. | USPAT; USOCR | OR | ON | 2005/03/04 10:06 |

| S89 | 1 | "5869983".PN. | USPAT; USOCR | OR | ON | 2005/03/04 10:05 |
|-----|------|--|---|----|----|------------------|
| S13 | 9 | ((((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 16:47 |
| S87 | 7523 | (714/25,30,43,44,724,728,733-735, 738,739,742).ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 16:41 |
| S79 | 147 | ((power voltage) near4 supply) same ((buffer I/O VDD\$4) near4 ring) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 16:40 |
| S86 | 1 | "3676777".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/22 15:03 |
| S85 | 1 | "4862075".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/22 15:03 |
| S84 | 1 | "5101150".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/22 15:03 |
| S83 | 1 | "5124638".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/22 15:03 |
| S82 | 1 | "5130646".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/22 15:02 |
| S81 | 1 | "5132613".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/22 15:02 |
| S80 | 1 | "5177437".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/22 15:01 |
| S78 | 44 | (((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and interference same supply | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 14:07 |

| S68 _. | 1167 | ((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 14:07 |
|------------------|------|---|---|----|----|------------------|
| S77 | 133 | (((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and interference | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 13:59 |
| S74 | 90 | (((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and test\$3 near4 (IC "integrated circuit" semiconductor) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 13:59 |
| S76 | 2 | (("low voltage differential signals" LVDS) same PLL) and LFSR | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 13:49 |
| S75 | 106 | ("low voltage differential signals" LVDS) same PLL | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 13:49 |
| S55 | 596 | ("low voltage differential signals" LVDS "double data rate" DDR) near4 interface | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 13:48 |
| S73 | 5 | (((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and ((DUT load) near4 board) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 13:23 |
| S69 | , 3 | (((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and DUT near4 board | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 13:16 |
| S72 | 1 | "4117400".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/22 13:14 |
| S71 | 1 | "4339673".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/22 13:14 |
| S70 | 1 | "4929888".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/22 13:14 |

| S65 | 2221 | (separate independent isolated) near4 ((supply near4 voltage) or ((power voltage) near4 supply)) same (buffer I/O interface VDD\$4) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 13:03 |
|-----|------|---|---|------|----|------------------|
| S67 | 50 | ((separate independent isolated) near4 ((supply near4 voltage) or ((power voltage) near4 supply)) same (buffer I/O interface VDD\$4)) and self-test\$7 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 10:49 |
| S66 | 1 | ((separate independent isolated) near4 ((supply near4 voltage) or ((power voltage) near4 supply)) same (buffer I/O interface VDD\$4)) and ("low voltage differential signals" LVDS "double data rate" DDR) same self-test\$7 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 10:48 |
| S64 | 5 | ("low voltage differential signals" LVDS "double data rate" DDR) near4 self-test\$7 and (volt\$3 power) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/22 10:47 |
| S63 | 51 | ((I/O near4 interface) same self-test\$7) not (((I/O near4 interface) same self-test\$7) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator")) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 16:11 |
| S62 | 11 | ((I/O near4 interface) same self-test\$7) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 16:11 |
| S61 | 0 | ((I/O near4 interface) same self-test\$7) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator") and ("multiple input shift register" MISR signature) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR . | ON | 2004/07/21 16:08 |
| S58 | | (("low voltage differential signals" LVDS "double data rate" DDR) near4 interface) and (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator") and ("multiple input shift register" MISR signature) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 16:08 |

| S60 | 62 | (I/O near4 interface) same self-test\$7 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 16:06 |
|-----|-----|--|---|----|----|------------------|
| S48 | | (((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) same (interface near4 (circuit device)) same (self-test "self test" self\$1test)) and ("multiple input shift register" MISR) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 16:05 |
| S59 | 2 | (DE-19832307\$ DE-19901460\$).did. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 14:59 |
| S57 | 13 | (("low voltage differential signals" LVDS "double data rate" DDR) near4 interface) and (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 14:28 |
| S56 | 3 | (("low voltage differential signals" LVDS "double data rate" DDR) near4 interface) and (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)) and ("multiple input shift register" MISR signature) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 14:28 |
| S54 | 26 | (interface near4 (circuit device)) same (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR) and ("multiple input shift register" MISR signature) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 14:25 |
| S53 | 31 | (interface near4 (circuit device)) same (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 14:11 |
| S52 | 13 | (interface near4 (circuit device)) same (self-test "self test" self\$1test) and (LFSR) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 14:11 |
| S51 | . 1 | (bidirectional\$2 bi-directional\$2) same (interface near4 (circuit device)) same (self-test "self test" self\$1test) and (LFSR) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 14:09 |

| S50 | 4 | ((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$). did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and ("multiple input shift register" MISR signature compact\$4) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 13:56 |
|-----|----|---|---|------|------|------------------|
| S49 | 3 | ((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$). did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and ("multiple input shift register" MISR signature) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 13:55 |
| S47 | 1 | ((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$). did. or (US-20020112206-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and ("multiple input shift register" MISR) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON · | 2004/07/21 13:47 |
| S14 | 84 | (((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) same (interface near4 (circuit device)) same (self-test "self test" self\$1test)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/21 13:46 |
| S46 | 1 | ((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$). did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and MISR | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR . | ON . | 2004/07/21 13:45 |
| S45 | 12 | (US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$). did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did. | US-PGPUB; USPAT | OR | OFF | 2004/07/21 13:44 |

| | | | or ocurcii iliotory | | | |
|-----|----|---------------|---------------------|----|------|------------------|
| S44 | 1 | "5230001".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:40 |
| S43 | 1 | "5459733".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:39 |
| S42 | 1 | "5621739".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:39 |
| S41 | 1 | "5869983".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:39 |
| S40 | 1 | "5321277".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:28 |
| S39 | 1 | "5321277".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:28 |
| S38 | 1 | "5416409".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:28 |
| S37 | 1 | "5423050".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:28 |
| S36 | 1 | "5416409".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:27 |
| S35 | 1 | "5423050".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:27 |
| S34 | 1 | "5444715".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:26 |
| S33 | 1 | "5473617".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:26 |
| S32 | 1 | "5535331".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:25 |
| S31 | 1 | "4646297".PN. | US-PGPUB; USPAT | OR | ÓN | 2004/07/21 10:15 |
| S30 | 1 | "5436908".PN. | US-PGPUB; USPAT | OR | ON ' | 2004/07/21 10:15 |
| S29 | 1 | "5578938".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:15 |
| S28 | 1 | "5894226".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:15 |
| S27 | 1 | "5991890".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:15 |
| S26 | 1 | "6016566".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:14 |
| S25 | 1 | "5619512".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:14 |
| S24 | 1. | "6105156".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:13 |
| S23 | 1 | "6112321".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:13 |

| S22 | 1 | "6114866".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:12 |
|-----|---|--|---|----|----|------------------|
| S21 | 1 | "6175939".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:12 |
| S20 | 1 | "6223312".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:12 |
| S19 | 1 | "6275057".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:12 |
| S18 | 1 | "6282680".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:10 |
| S17 | 1 | "6347387".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:09 |
| S16 | 1 | "6397363".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:08 |
| S15 | 1 | "6477674".PN. | US-PGPUB; USPAT | OR | ON | 2004/07/21 10:08 |
| S12 | 0 | (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not ((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/20 16:30 |
| S11 | 0 | (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not ((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/20 16:30 |

| S10 . | 51 | ((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/20 16:30 |
|-------|-----|---|---|------|----|------------------|
| S8 | 42 | ((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/20 16:25 |
| S9 | 626 | (((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/20 16:24 |
| S6 | 435 | (((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/20 16:24 |
| S7 | 1 | (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) and (\$6random near6 generat\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/20 16:06 |
| S5 | 32 | ((interface near4 (circuit device)) and (Britt Harris Dooley).XA.) and "714"/\$.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/20 15:58 |
| S4 | 94 | (interface near4 (circuit device)) and (Britt Harris Dooley).XA. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR · | ON | 2004/07/20 15:19 |
| S3 | 70 | (interface and (Britt Harris Dooley). XA.) and "714"/\$.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/20 15:18 |

| S2 | 44538 | "714"/\$.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR . | ON | 2004/07/20 15:18 |
|----|-------|---|---|------|----|------------------|
| S1 | 370 | interface and (Britt Harris Dooley). XA. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/07/20 15:18 |

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